

## Special Issue

# Electromagnetic Nondestructive Testing and Evaluation

### Message from the Guest Editor

Electromagnetic nondestructive testing is playing a significant part in nondestructive testing around the world. The developing usage of electromagnetic nondestructive testing has put forward new requirements and challenges for promoting research in related fields. Therefore, this Special Issue aims to introduce new ideas and experimental results from the principle, characterization and mechanism of electromagnetic nondestructive testing to sensors, signal processing and intelligent evaluation in practical applications. This Special Issue will publish high-quality original research papers in the following fields:

- Principle and mechanism of electromagnetic nondestructive testing method;
- Electromagnetic characterization of electromagnetic excitation and damage or tension;
- Magneto-electric coupling and sensing mechanism and technology;
- Electromagnetic nondestructive testing electrical signal processing;
- Electromagnetic nondestructive testing digital signal processing and intelligent evaluation;
- Electromagnetic nondestructive testing sensors, equipment and applications.

---

### Guest Editor

Prof. Dr. Yanhua Sun

State Key Laboratory of Digital Manufacturing Equipment and Technology, School of Mechanical Science and Engineering, Huazhong University of Science and Technology (HUST), Wuhan 430074, China

---

### Deadline for manuscript submissions

closed (20 January 2024)



## Applied Sciences

---

an Open Access Journal  
by MDPI

---

Impact Factor 2.5  
CiteScore 5.5



[mdpi.com/si/157025](https://mdpi.com/si/157025)

*Applied Sciences*  
Editorial Office  
MDPI, Grosspeteranlage 5  
4052 Basel, Switzerland  
Tel: +41 61 683 77 34  
[applsci@mdpi.com](mailto:applsci@mdpi.com)

[mdpi.com/journal/  
applsci](https://mdpi.com/journal/applsci)





# Applied Sciences

---

an Open Access Journal  
by MDPI

---

Impact Factor 2.5  
CiteScore 5.5



[mdpi.com/journal/  
applsci](https://mdpi.com/journal/applsci)



## About the Journal

### Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal *Applied Sciences* has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

---

### Editor-in-Chief

Prof. Dr. Giulio Nicola Cerullo  
Dipartimento di Fisica, Politecnico di Milano, Piazza L. da Vinci 32,  
20133 Milano, Italy

---

### Author Benefits

#### Open Access:

free for readers, with article processing charges (APC) paid by authors or their institutions.

#### High Visibility:

indexed within Scopus, SCIE (Web of Science), Ei Compendex, Inspec, Embase, CAPIus / SciFinder, and other databases.

#### Journal Rank:

JCR - Q2 (Engineering, Multidisciplinary) / CiteScore - Q1 (General Engineering )